04

X 射线衍射仪　型号：Nanopix

X-ray diffractometer

主要功能

物相及织构测定：
常温
变温
原位拉伸

样品要求

丝
粉末
块状
原位拉伸

主要技术指标

靶材：Mo
靶电压：　50 KV
靶电流：　24 mA
Kα 纯度：99.95%
入射瞄准仪：ϕ0.3 mm，ϕ0.5 mm,
探测器：超高速二维硅像素探测器
像素尺寸：100×100 μm
像素数：596,000 个
附件：原位变温及拉伸台

仪器开放共享收费标准

测试项目	收费标准	
	校内	校外
物相测试		
原位测试		

应用案例

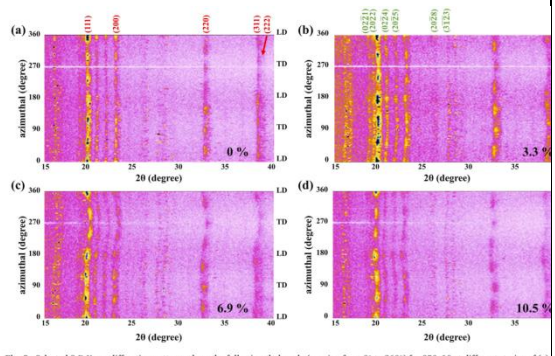

Fig. 8. Selected 2-D X-ray diffraction patterns along the full azimuthal angle (ranging from 0° to 360°) for 850–10 at different strains of (a) 3.3 %; (c) 6.9 %, (d) 10.5 %.

L. Deng et al. INT J PLASTICITY. 175 (2024) 103929

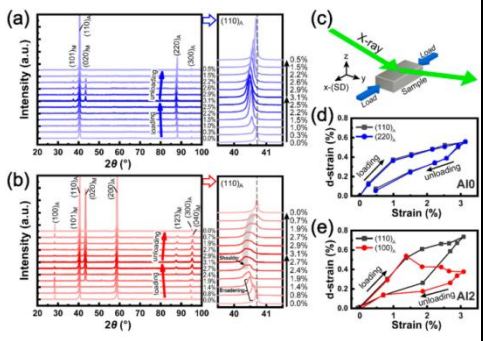

Figure 3. (a, b) XRD patterns of (a) AI0 and (b) AI2 alloys during loading and unloading at room temperature; zoomed-in vi in the right panel. (c) Schematic diagram for the *in situ* XRD experiment. (d, e) Lattice strains in the direction transverse direction associated with several B2 reflections of (d) AI0 and (e) AI2 alloys.

C. SONG ET AL. MATER. RES. LETT. 2023. 11(11). 925–932